





Sensor QA stations






Daniele De Gruttola
University & INFN of Salerno
ddegruttola@unisa.it









Kick-off to define QA protocol(s)

-  Define pipeline for QA on SiPMs
-  Tests to be performed at different stages and with different scopes
-  **Possibility to perform “basic” tests in parallel (2/3 sites)**
-  **Possibility to perform specific tests in one site**











SiPM matrices for the dRICH

-  ~5000 SiPM matrices will be built and delivered by Hamamatsu
-  Each matrix has 64 sensors
-  4 matrices will be installed a carrier
-  1248 carriers
-  **Assembling matrices into carriers will be done by a company**

QA tests - when, where

-  QA tests on sensor matrices ?
-  Maybe not useful - to be decided according to needs and costs
-  Maybe test on a sub-sample?
-  Test on matrix before assembling could be useful to be sure that matrices with similar parameters go into one carrier?
-  Investigate possibility to perform these tests in Hamamatsu? Costs?
-  Tests in our QA hub after assembling on carriers

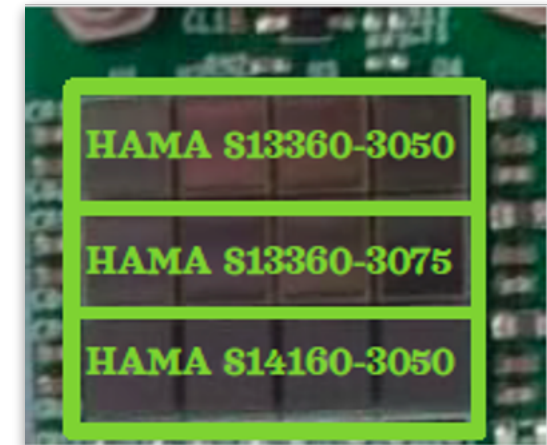
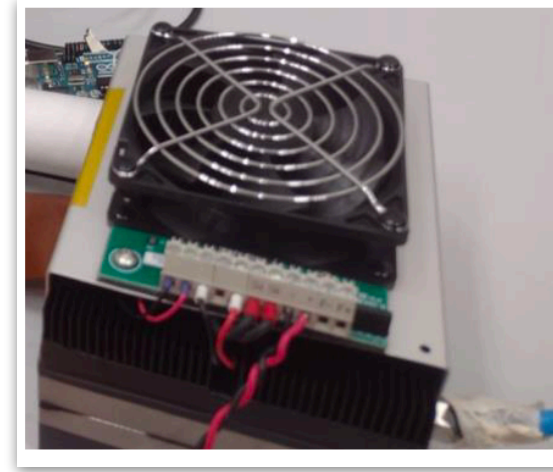
QA tests - what

-  Electrical inspection (on nude matrix? on assembled carrier?)
-  IV curves, breakdown
-  Tests vs temperature
-  Ensure to be stable in temperature (**work done and in progress in Salerno and Cosenza**)
-  Define three T values to perform IV characterization (-20°C , 0°C , 20°C or 0°C , 10°C , 20°C)
-  Tests at -40°C on a subsample (1-2%?)
-  Check V bias trending vs T
-  **Optical inspection** (before and after assembling?)
 -  Microscopes are available in Catania
 -  Procedure to remove scratches well known (tested in Bologna)

Set-up to test SiPMs @UNICAL

Bench for SiPMs characterization in Cosenza radiation lab

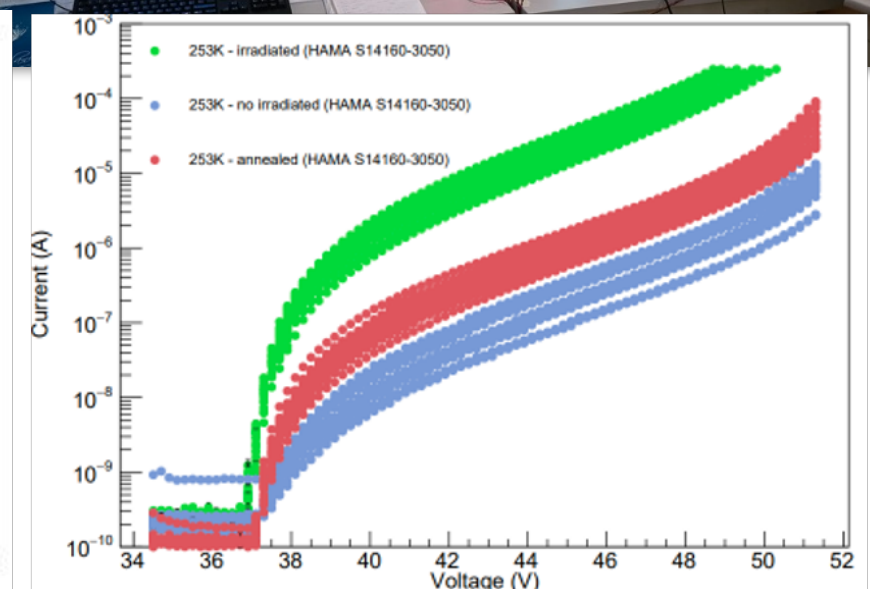
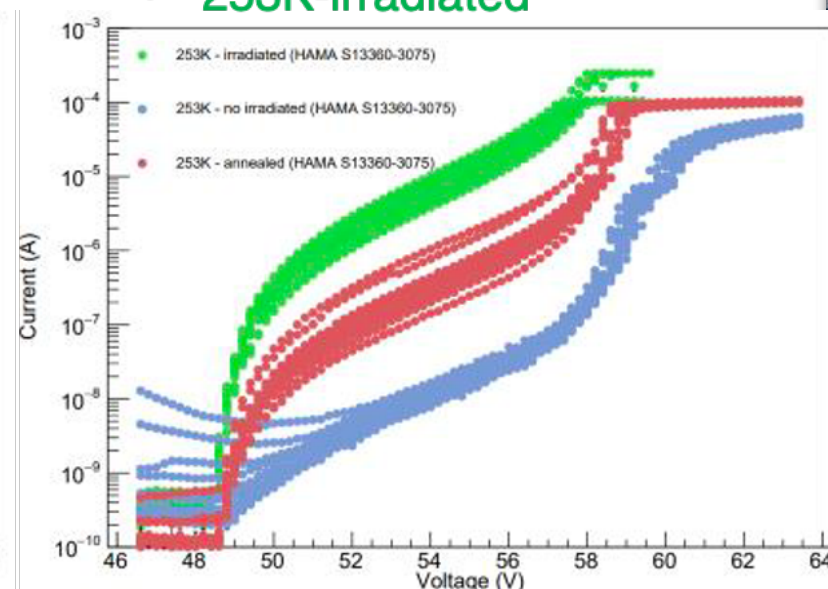
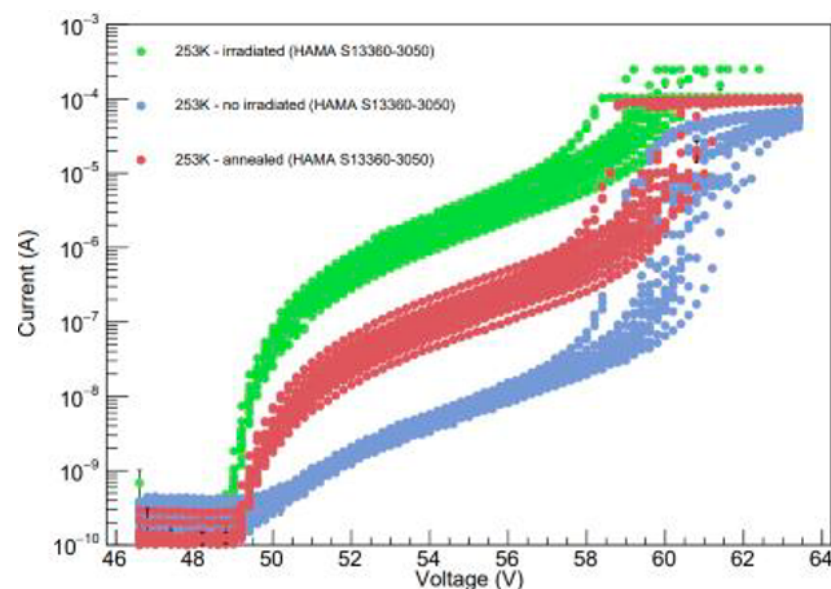
- Setup specifically designed to measure DCR
- dark current versus reverse bias voltage
- more details in backup



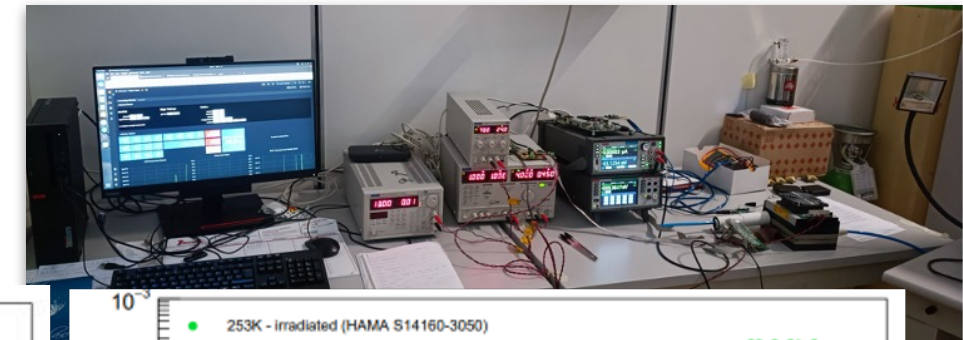
Example of studies performed in 2023-2024

- Three types of Hamamatsu sensors tested
- Irradiation tests: protons (TIFPA-Trento); neutrons (CN-Legnaro); gamma (GIF-CERN)
- SiPMs characterization: study of damage by protons and gammas

IV-curves



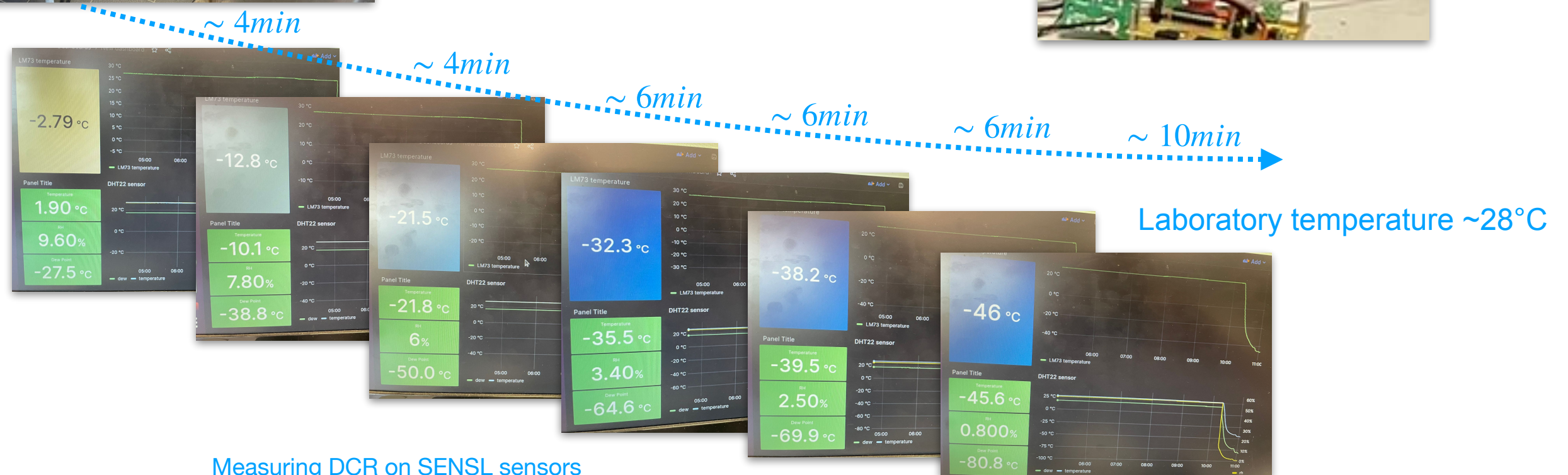
- 253K-no irradiated
- 253K-annealed
- 253K-irradiated



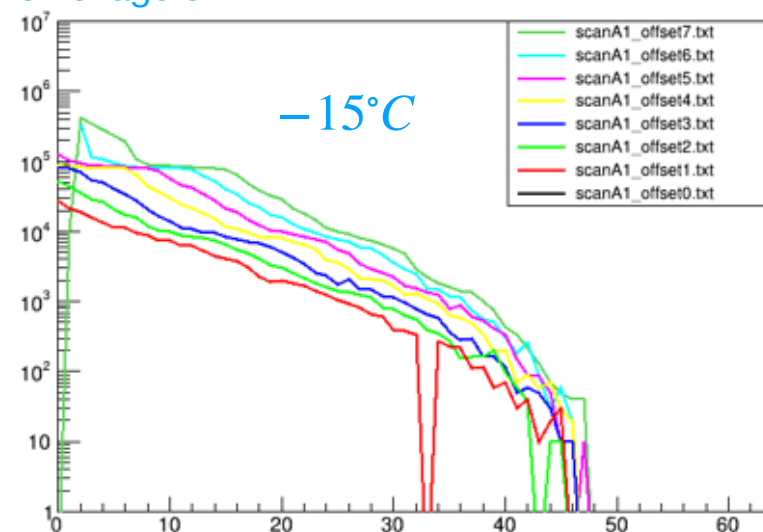
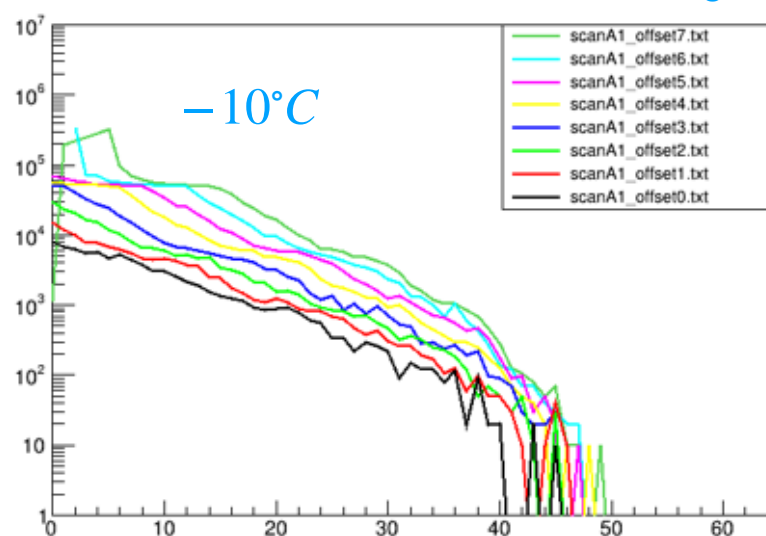
Studies on energy scan (backup)

Set-up to test SiPM @UNISA

- Idea to build a larger AirBox and use a dewar to go down in temperature
- AirBox + Peltier + dewar (SiPM HV on)
Low temperature far away from dew point



Measuring DCR on SENSL sensors
breakdown voltage 24C, overvoltage 6V



Salerno lab is currently being equipped with the same setup built in Cosenza (installing DAQ + multiplexer)

Possible test flow

1) Hamamatsu → company → QA hub in Cosenza-Salerno-Trieste

Optical inspection
Assembling

Complete QA

2) Hamamatsu → Catania → company → QA hub in Cosenza-Salerno-Trieste

Optical inspection

Assembling

Complete QA

3) Other possible options

Trieste is equipping a lab to make studies on microscopic behavior of sensors

Available to be part of the QA hub

Timeline for QA

Estimate total time needed for tests

Experience from JUNO in Catania

Step	Action	Time/Action [min/Action]	Number of Actions	Total time [min]	Notes
0	Optical inspection	1/tile	16	16	
1	Assembling 16 matrices on PCB	1/tile	16	16	
2	Cooling at -50°C	30+15	1	45	4.5°C - 5°C/min + 15 min stability
3	IV-curve Dark	0.5/curve - 1/curve	16x16(=32/2)	128 - 256	Ammeter w/ 2 channels
4	IV-curve Light	0.5/curve - 1/curve 0.3/DS	16x16	128 - 256 + 11	
5	Charge spectrum Dark	1.5/16 spectra/ Vpoint	32x5 Vpoint	240	1kHz event rate
6	Charge spectrum Light	1.5/16 spectra/ Vpoint	32x5 Vpoint	240 + 11	
7	Going up to environment T	20+10	1	30	
8	Removing 16 matrices	1/tile	16	16	
9	Logbook + DB	5+5	2	10	Writing notes + data sharing
CASE 1	Only IV-curve no charge spectra		359 (6h)	359 (6h)	1538 h (193 shifts)
CASE 2	No IV, only charge spectra		582 (9.7h)	582 (9.7h)	2486 h (311 shifts)
CASE 3	IV and charge spectra		850 (14.2h)	850 (14.2h)	3639 h (459 shifts)
CASE 4	I-V and 10% charge spectra		420 (7h)	420 (7h)	1794 h (225 shifts)

Timeline for QA

Consider Catania-Cosenza-Salerno-Trieste + Hamamatsu delivery + assembling in company



Estimate total time needed for tests

Our table to be defined (study of protocols and time estimate)






next: remove “?” and establish detailed needs

Step	Action	Where	Number of Actions	Total time	Notes
0	Optical inspection	Catania? Company?	?	?	Microscope
1	Assembling 4 matrices	Company	?	?	
2	IV-curve Dark at T_1	dRICH QA hub	?	2h?	Testing in CS-SA labs
3	IV-curve Light at T_1	dRICH QA hub	?	2h?	Testing in CS-SA labs
4	IV-curve Dark at T_2	dRICH QA hub	?	2h?	Testing in CS-SA labs
5	IV-curve Light at T_2	dRICH QA hub	?	2h?	Testing in CS-SA labs
6	IV-curve Dark at T_3	dRICH QA hub	?	2h?	Testing in CS-SA labs
7	IV-curve Light at T_3	dRICH QA hub	?	2h?	Testing in CS-SA labs
8	IV-curve Light at -40°C	dRICH QA hub	?	2h?	Sub-sample
9	Logbook + DB	dRICH QA hub	?	0.5h?	Writing notes + data sharing
Define cases	according to previous considerations			?	shifts?





Current manpower in Catania

-  1 tenured faculty: *Cristina Tuvé*
-  1 undergrad student

Current manpower in Cosenza

-  3 tenured faculties: *Enrico Tassi, Marcella Capua, Salvatore Fazio*
-  1 PhD student: *Luisa Occhiuto*
-  1 undergrad student: *Cristian Romeo*
-  1 technician: *Vittorio Romano*
-  Hiring manpower dedicated to QA tests: 1 postdoc + undergraduates and a master student

Current manpower in Salerno

-  3 tenured faculties: *Daniele De Gruttola, Annalisa De Caro, Alberto Calivà*
-  1 postdoc: *Cristina Ripoli*
-  1 technician: *Nicola Funicello*
-  Possibly hiring manpower dedicated to QA tests in the future (students+tenured faculties)

+ Trieste

- Continuous activity in our sites foreseen during QA phases
- Shifts to be performed by dedicated people

Conclusions

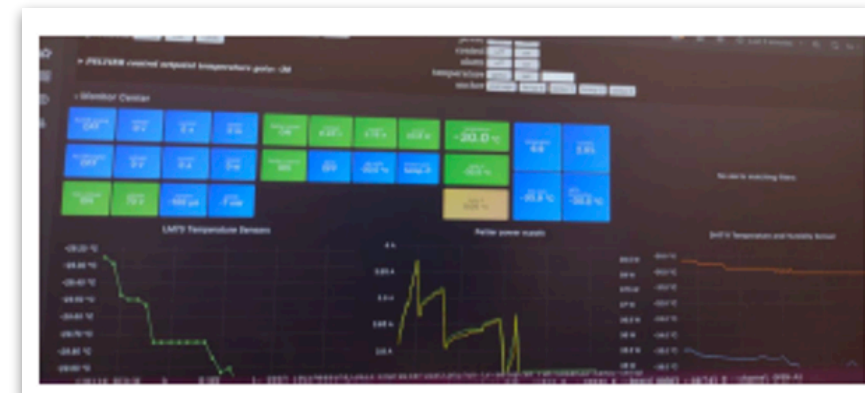
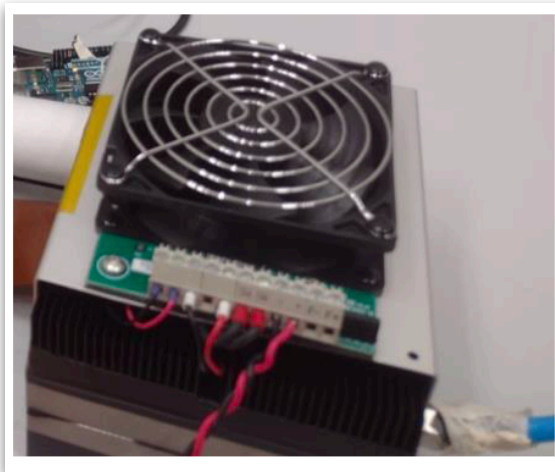
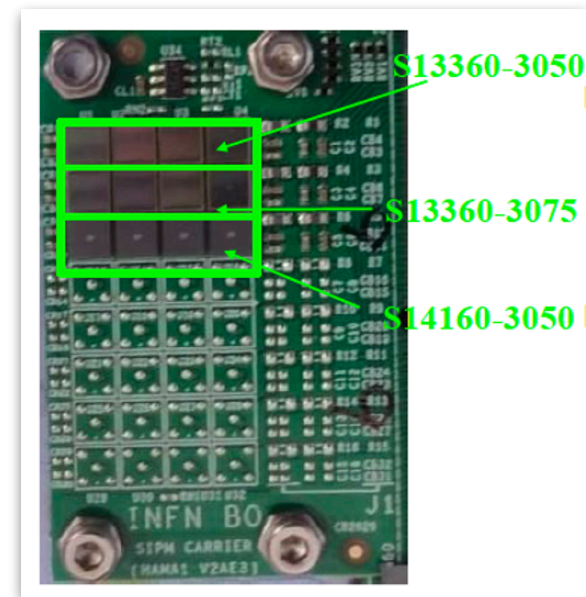
- **Available manpower** from Catania-Cosenza-Salerno-Trieste
- **Laboratories** equipped and operational in Cosenza and Salerno (and Trieste)
- Characterization studies performed and QA protocol to be defined
- Sites can perform **QA tests in parallel**
- **Redundancy** is also crucial as backup in case of issues
- Ongoing brain-storming in Bologna-Catania-Cosenza-Salerno-Trieste groups
- Test pipeline being defined to be ready in ~1 year
- **Detailed pipeline, database and checklist** will be crucial

Backup

Set-up to test SiPMs @UNICAL

Experimental setup in Cosenza

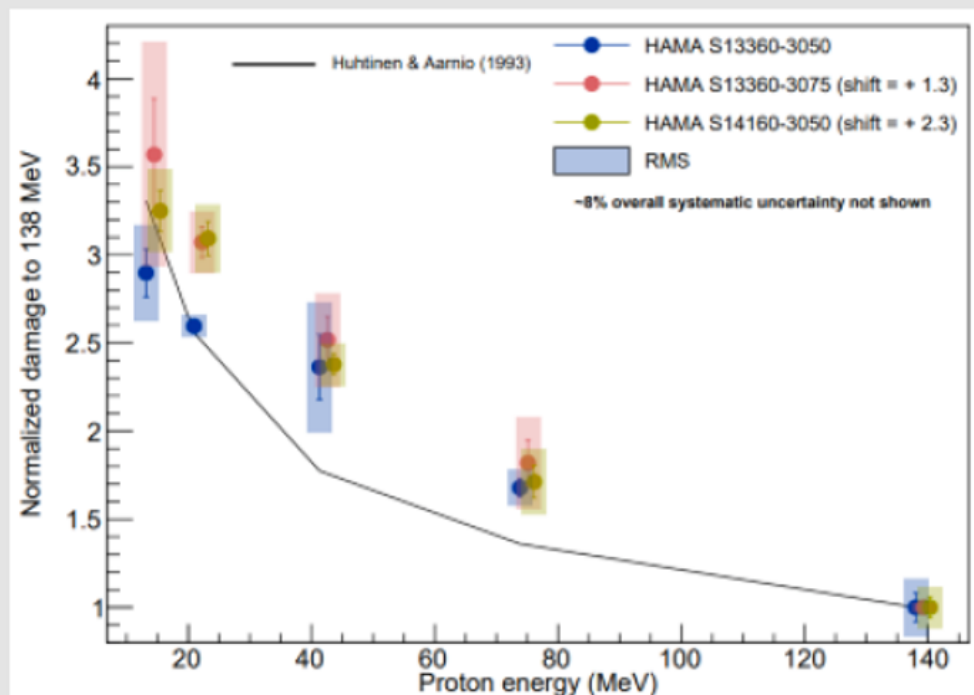
- boards hosting **SiPMs**
- custom made portable **Peltier box**
- ultrapure air tanks to **control humidity** in the inner box
- Adapter** board to regulate the **voltage** supplied to the SiPMs
- ALCOR** board for the data acquisition
- A relative **humidity and temperature sensor** (Arduino)
- A **Master Logic** board for communication with the adapter board
- An **FPGA** to program and read the ALCOR data
- Grafana* web application to monitor operations



PRELIMINARY RESULTS

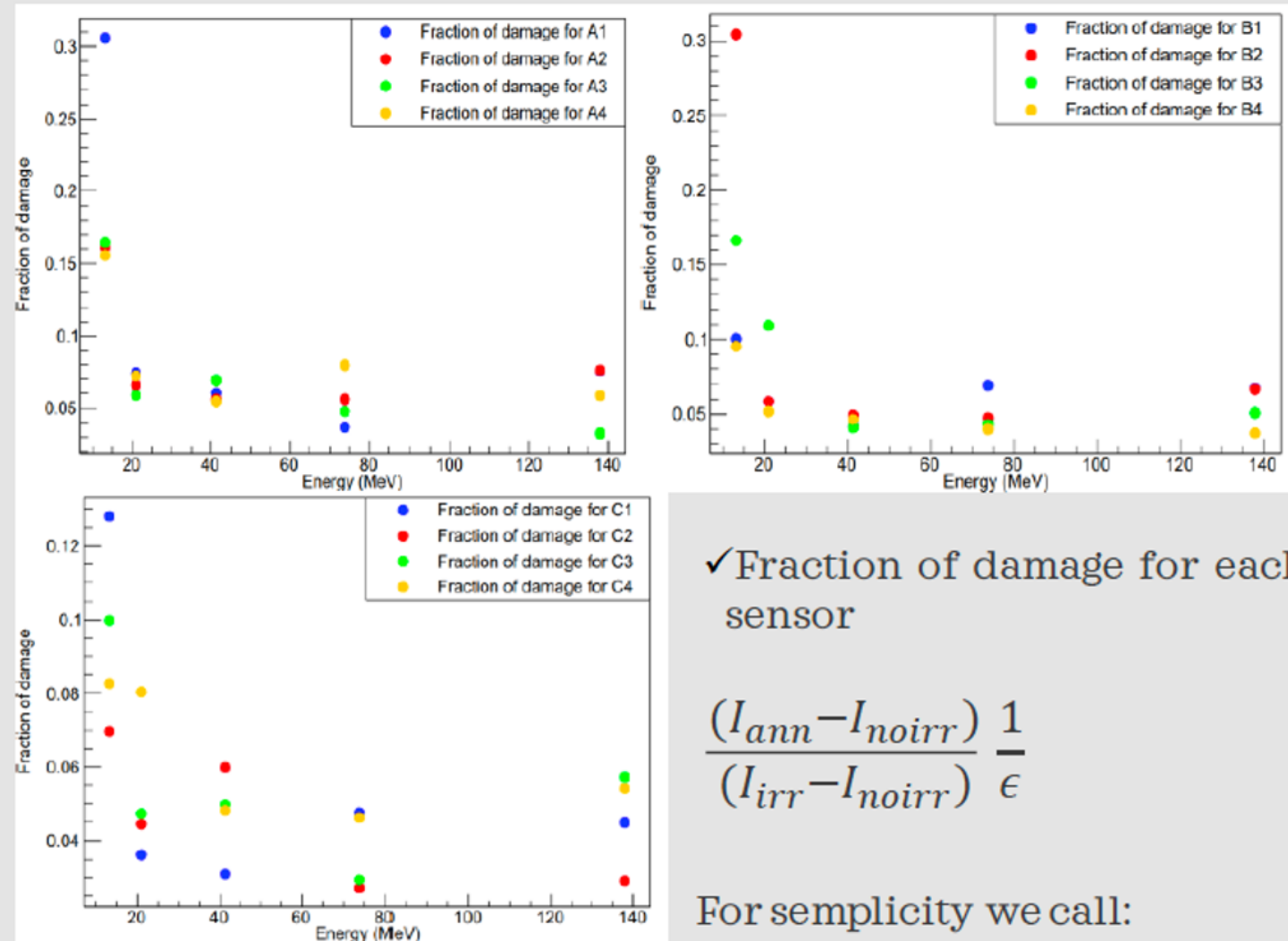
ENERGY SCAN

Overvoltage = Dark current - V_{bd}



- ✓ Comparison of radiation damage for each sensor vs radiation damage by NIEL.

$$\frac{(I_{irr} - I_{noirr})}{(I_{irr} - I_{noirr})(138 \text{ MeV})} \frac{1}{\epsilon} \quad \epsilon = \text{efficiency of degrader.}$$



- ✓ Fraction of damage for each sensor

$$\frac{(I_{ann} - I_{noirr})}{(I_{irr} - I_{noirr})} \frac{1}{\epsilon}$$

For simplicity we call:

- HAMA S13360-3050 == A
- HAMA S13360-3075 == B
- HAMA S14160-3050 == C